

<b>Notice of References Cited</b>	Application/Control No. 10/582,477		Applicant(s)/Patent Under Reexamination FITZ ET AL.	
	Examiner Kristina R. Fulton		Art Unit 3673	Page 1 of 2

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-1,885,957 A	11-1932	ELWOOD SINGLETON ROSCOE	70/456R
*	B	US-2,694,244 A	11-1954	NOLAN NICHOLAS J	24/650
*	C	US-3,349,589 A	10-1967	ALEX FRICKE	70/395
*	D	US-3,427,834 A	02-1969	TUTINO DOMINICK J	70/414
*	E	US-4,888,970 A	12-1989	Kinzler et al.	70/456R
*	F	US-6,016,676 A	01-2000	McConnell, John E.	70/408
*	G	US-6,216,501 B1	04-2001	Marquardt et al.	70/252
*	H	US-6,460,386 B1	10-2002	Watanuki et al.	70/456R
*	I	US-6,474,123 B1	11-2002	Kito et al.	70/456R
*	J	US-6,553,802 B1	04-2003	Jacob, Dirk	70/456R
*	K	US-6,647,752 B1	11-2003	Chaillie, Frederic	70/456R
*	L	US-6,705,141 B1	03-2004	Jacob et al.	70/408
*	M	US-2004/0148988 A1	08-2004	Taylor, Mark Raymond	070/408

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	I					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/582,477		Applicant(s)/Patent Under Reexamination FITZ ET AL.	
	Examiner Kristina R. Fulton		Art Unit 3673	Page 2 of 2

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0103070 A1	05-2005	Meyerson et al.	070/456.00R
*	B	US-2005/0166650 A1	08-2005	Shimura et al.	070/252
*	C	US-2005/0223766 A1	10-2005	Hashimoto et al.	070/456.00R
*	D	US-2006/0016231 A1	01-2006	Khounsombath et al.	070/456.00R
*	E	US-2006/0010944 A1	01-2006	Balko et al.	070/456.00R
*	F	US-2006/0150696 A1	07-2006	Eychenne et al.	070/456.00R
*	G	US-7,098,791 B2	08-2006	Okada, Hirofumi	340/568.1
*	H	US-2007/0000295 A1	01-2007	Donner et al.	070/271
*	I	US-2007/0266748 A1	11-2007	Fitz et al.	070/395
*	J	US-2008/0127693 A1	06-2008	Cadiz et al.	70/456.R
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.